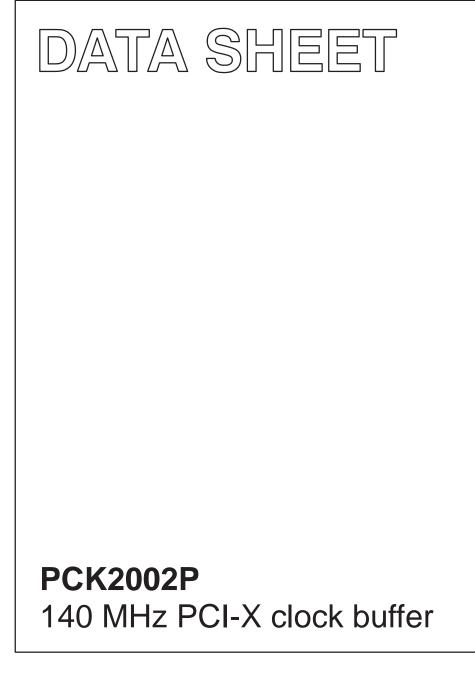
# INTEGRATED CIRCUITS



Product data

2001 May 09

File under Integrated Circuits ICL03





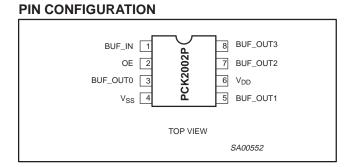
# **PCK2002P**

### **FEATURES**

- General purpose and PCI-X 1:4 clock buffer
- 8-pin TSSOP package
- See PCK2001 for 48-pin 1:18 buffer part
- See PCK2001M for 28-pin 1:10 buffer part
- See PCK2001R for 16-pin 1:6 buffer part
- Operating frequency: 0 140 MHz
- Part-to-part skew < 500 ps</li>
- Low output skew: <200 ps</li>
- 3.3 V operation
- ESD classification testing is done to JEDEC Standard JESD22. Protection exceeds 2000 V to HBM per method A114.

### DESCRIPTION

The PCK2002PL is a 1–4 fanout buffer used as a high-performance, low skew, general purpose and PCI-X clock buffer. It distributes one input clock (BUF\_IN) signal to four output clocks ( $BUF_OUT_n$ ).



## **PIN DESCRIPTION**

PIN NUMBER	I/O TYPE	SYMBOL	FUNCTION
1	Input	BUF_IN	Buffered clock input
3, 5, 7, 8	Output	BUF_OUT (0-3)	Buffered clock outputs
6	Input	V <sub>DD</sub>	3.3 V supply
2	Input	OE	Output Enable
4	Input	V <sub>SS</sub>	Ground

### QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay BUF_IN to BUF_OUT <sub>n</sub>	$V_{CC} = 3.3 \text{ V}, C_L = 25 \text{ pF}$	2.9 2.8	ns
t <sub>r</sub>	Rise time	$V_{CC}$ = 3.3 V, $C_L$ = 25 pF, 0.2V_{DD} to 0.6V_{DD}	800	ps
t <sub>f</sub>	Fall time	$V_{CC}$ = 3.3 V, $C_L$ = 25 pF, 0.6V_{DD} to 0.2V_{DD}	600	ps
I <sub>CC</sub>	Total supply current	V <sub>CC</sub> = 3.6 V	50	μΑ

### **ORDERING INFORMATION**

PACKAGES	TEMPERATURE RANGE	ORDER CODE	DRAWING NUMBER
8-Pin Plastic TSSOP	−40 to +85 °C	PCK2002PDP	SOT505-1
8-Pin Plastic SO	−40 to +85 °C	PCK2002PD	SOT96-1

# PCK2002P

### **FUNCTION TABLE**

OE	BUF_IN	BUF_OUTn
L	Х	L
Н	L	L
Н	Н	Н

### ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>

In accordance with the Absolute Maximum Rating System (IEC 134). Voltages are referenced to  $V_{SS}$  ( $V_{SS} = 0$  V).

SYMBOL	DADAMETED	CONDITION	LI	LINUT	
STMBOL	PARAMETER	CONDITION	MIN	MAX	UNIT
V <sub>DD</sub>	DC 3.3 V supply voltage		-0.5	+4.3	V
I <sub>IK</sub>	DC input diode current	V <sub>1</sub> < 0	—	-50	mA
VI	DC input voltage	Note 2	-0.5	V <sub>DD</sub> + 0.5	V
I <sub>OK</sub>	DC output diode current	$V_{O} > V_{DD}$ or $V_{O} < 0$	—	±50	mA
Vo	DC output voltage	Note 2	-0.5	V <sub>DD</sub> + 0.5	V
Ι <sub>Ο</sub>	DC output source or sink current	$V_O \ge 0$ to $V_{DD}$	—	±50	mA
T <sub>stg</sub>	Storage temperature range		-65	+150	°C
P <sub>tot</sub>	Power dissipation per package plastic medium-shrink SO (SSOP)	For temperature range: 0 to +70 °C above +55 °C derate linearly with 11.3 mW/K	—	850	mW

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	CONDITIONS	LIM	UNIT	
STWBUL	PARAMETER	CONDITIONS	MIN	MAX	UNIT
V <sub>DD</sub>	DC 3.3V supply voltage		3.0	3.6	V
CL	Capacitive load		20	30	pF
VI	DC input voltage range		0	V <sub>DD</sub>	V
Vo	DC output voltage range		0	V <sub>DD</sub>	V
T <sub>amb</sub>	Operating ambient temperature range in free air		-40	+85	°C

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### DC CHARACTERISTICS

		TEST CONDITIONS			LIMITS T <sub>amb</sub> = -40 to +85 °C		UNIT
SYMBOL	PARAMETER						
		V <sub>DD</sub> (V)	V) OTHER		MIN	MAX	
V <sub>IH</sub>	HIGH level input voltage	3.0 to 3.6	—	_	2.0	V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	LOW level input voltage	3.0 to 3.6	—	—	V <sub>SS</sub> – 0.3	0.8	V
		3.0 to 3.6	I <sub>OH</sub> = -1 mA	—	V <sub>DD</sub> – 0.2	—	V
V <sub>OH</sub>	H Output HIGH voltage	3.0	I <sub>OH</sub> = -24 mA	—	2.0	_	V
		3.0	I <sub>OH</sub> = -12 mA	—	2.4	—	V
		3.0 to 3.6	I <sub>OL</sub> = 1 mA	_	_	0.2	V
V <sub>OL</sub>	Output LOW voltage	3.0	I <sub>OL</sub> = 24 mA	_	_	0.8	V
		3.0	I <sub>OL</sub> = 12 mA	—	—	0.55	V
		3.0	V <sub>OUT</sub> = 1 V	_	-50	_	mA
ЮН	Output HIGH current	3.3	V <sub>OUT</sub> = 1.65 V	—	_	-150	mA
		3.0	V <sub>OUT</sub> = 2.0 V	_	60	_	mA
IOL	Output LOW current	3.3	V <sub>OUT</sub> = 1.65 V	—	_	150	mA
±II	Input leakage current	3.6	$V_{I} = V_{DD}$ or GND	—	_	±5	μΑ
I <sub>CC</sub>	Quiescent supply current	3.6	$V_{I} = V_{DD}$ or GND	l <sub>O</sub> = 0	_	100	μΑ

# PCK2002P

#### **AC CHARACTERISTICS**

SYMBOL	PARAMETER	TEST CONDITIONS		LIMITS T <sub>amb</sub> = -40 to +85 °C			UNIT
			NOTES	MIN	TYP <sup>6</sup>	MAX	
T <sub>H</sub>	CLK HIGH time	66 MHz	2	6.0	—	—	ns
TL	CLK LOW time		3	6.0	—	—	ns
T <sub>H</sub>	CLK HIGH time	140 MHz	2	2.9	—	—	ns
TL	CLK LOW time	140 MHZ	3	3.0	—	—	ns
T <sub>R</sub>	Output rise slew rate		4	1.4	1.7	4.0	V/ns
T <sub>F</sub>	Output fall slew rate		4	1.5	2.2	4.0	V/ns
T <sub>PLH</sub>	Buffer LH propagation delay		5	1.8	2.9	3.4	ns
T <sub>PHL</sub>	Buffer HL propagation delay		5	1.8	2.8	3.4	ns
Т <sub>SKW</sub>	Bus CLK skew		1	_	_	200	ps
T <sub>DDSKW</sub>	Device to device skew		1	_	_	500	ps

NOTES:

1. CLK skew is only valid for equal loading of all outputs.

2.  $T_H$  is measured at 0.5  $V_{DD}$  as shown in Figure 2. 3.  $T_L$  is measured at 0.35  $V_{DD}$  as shown in Figure 2. 4.  $T_R$  and  $T_F$  are measured as a transition through the threshold region 0.2  $V_{DD}$  to 0.6  $V_{DD}$  and 0.6  $V_{DD}$  to 0.2  $V_{DD}$ . 5. Input edge rate for these tests must be faster than 1 V/ns.

6. All typical values are at  $V_{CC} = 3.3$  V and  $T_{amb} = 25$  °C.

#### **AC WAVEFORMS**

 $V_M = 50\% V_{DD}$ 

 $C_{L}^{...} = 25 \text{ pF}$ 

 $\bar{V_{OL}}$  and  $\bar{V}_{OH}$  are the typical output voltage drop that occur with the output load.

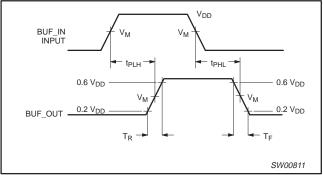


Figure 1. Load circuitry for switching times.

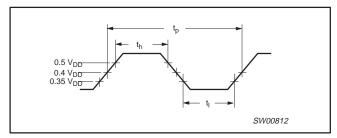


Figure 2. Buffer Output clock

### **TEST CIRCUIT**

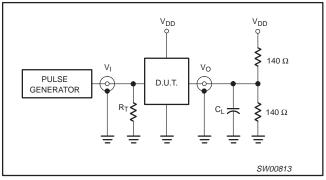
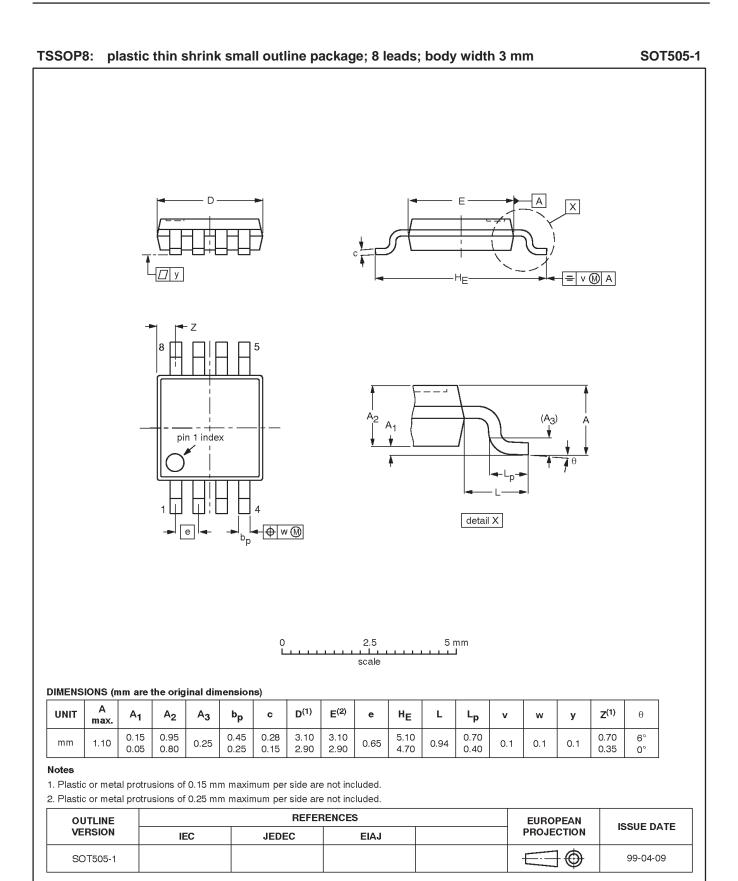


Figure 3. Load circuitry for switching times

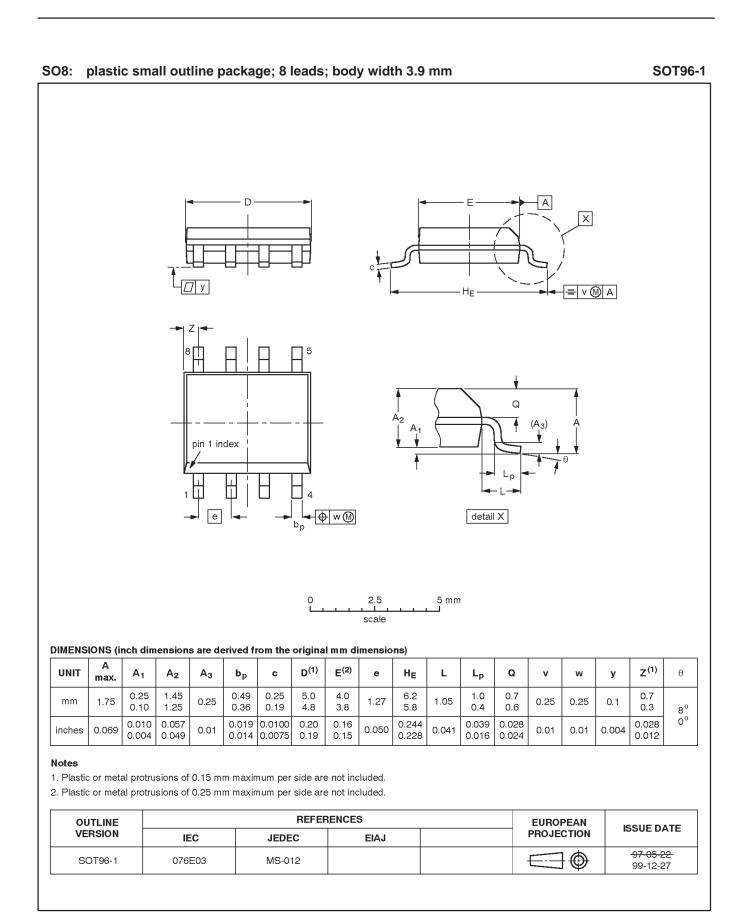
PCK2002P

Product data



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### Data sheet status

Data sheet status <sup>[1]</sup>	Product status <sup>[2]</sup>	Definitions
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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